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July 2010

FDME1034CZT

Complementary PowerTrench® MOSFET

N-channel: 20 V, 3.8 A, 66 m Ω P-channel: -20 V, -2.6 A, 142 m Ω

Features

Q1: N-Channel

- Max $r_{DS(on)}$ = 66 m Ω at V_{GS} = 4.5 V, I_D = 3.4 A
- Max $r_{DS(on)} = 86 \text{ m}\Omega$ at $V_{GS} = 2.5 \text{ V}$, $I_D = 2.9 \text{ A}$
- Max $r_{DS(on)} = 113 \text{ m}\Omega$ at $V_{GS} = 1.8 \text{ V}$, $I_D = 2.5 \text{ A}$
- Max $r_{DS(on)} = 160 \text{ m}\Omega$ at $V_{GS} = 1.5 \text{ V}$, $I_D = 2.1 \text{ A}$

Q2: P-Channel

- Max $r_{DS(on)}$ = 142 m Ω at V_{GS} = -4.5 V, I_D = -2.3 A
- Max $r_{DS(on)} = 213 \text{ m}\Omega$ at $V_{GS} = -2.5 \text{ V}$, $I_D = -1.8 \text{ A}$
- Max $r_{DS(on)} = 331 \text{ m}\Omega$ at $V_{GS} = -1.8 \text{ V}$, $I_D = -1.5 \text{ A}$
- Max $r_{DS(on)}$ = 530 m Ω at V_{GS} = -1.5 V, I_D = -1.2 A
- Low profile: 0.55 mm maximum in the new package MicroFET 1.6x1.6 **Thin**
- Free from halogenated compounds and antimony oxides
- HBM ESD protection level > 1600 V (Note 3)
- RoHS Compliant



This device is designed specifically as a single package solution for a DC/DC 'Switching' MOSFET in cellular handset and other ultra-portable applications. It features an independent N-Channel & P-Channel MOSFET with low on-state resistance for minimum conduction losses. The gate charge of each MOSFET is also minimized to allow high frequency switching directly from the controlling device.

The MicroFET 1.6x1.6 **Thin** package offers exceptional thermal performance for it's physical size and is well suited to switching and linear mode applications.

Applications

- DC-DC Conversion
- Level Shifted Load Switch



MicroFET 1.6x1.6 Thin

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

| Symbol | ymbol Parameter | | | Q1 | Q2 | Units |
|-----------------------------------|--|------------------------|-----------|-------|---------|-------|
| V _{DS} | Drain to Source Voltage | | | 20 | -20 | V |
| V _{GS} | Gate to Source Voltage | | | ±8 | ±8 | V |
| | Drain Current -Continuous | T _A = 25 °C | (Note 1a) | 3.8 | -2.6 | ^ |
| ID | -Pulsed | | | 6 | -6 | A |
| D | Power Dissipation for Single Operation $T_A = 25 ^{\circ}\text{C}$ (Note 1a) | | | 1.4 | W | |
| P_{D} | Power Dissipation for Single Operation T _A = 25 °C (Note 1b) 0.6 | | VV | | | |
| T _J , T _{STG} | Operating and Storage Junction Tempera | ature Range | | -55 t | to +150 | °C |

Thermal Characteristics

| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient (Single Operation) | (Note 1a) | 90 | °C/W |
|-----------------|--|-----------|-----|------|
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient (Single Operation) | (Note 1b) | 195 | C/VV |

Package Marking and Ordering Information

| Device Marking | Device | Package | Reel Size | Tape Width | Quantity |
|----------------|-------------|------------------------------|-----------|------------|------------|
| 5T | FDME1034CZT | MicroFET 1.6x1.6 Thin | 7 " | 8 mm | 5000 units |

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

| Symbol | Parameter | Test Conditions | Туре | Min | Тур | Max | Units |
|--|-----------------------------------|--|------|-----|-----|-----|---------|
| Off Chara | cteristics | | | | | | |
| BV _{DSS} | Drain to Source Breakdown Voltage | $I_D = 250 \mu A, V_{GS} = 0 V$ | Q1 | 20 | | | V |
| Drain to Source Breakdown voltage | $I_D = -250 \mu A, V_{GS} = 0 V$ | Q2 | -20 | | | V | |
| ΔBV _{DS} S ΔΤ _J | | $I_D = 250 \mu A$, referenced to 25 °C | Q1 | | 16 | | mV/°C |
| ΔT_{J} | Coefficient | I_D = -250 μ A, referenced to 25 °C | Q2 | | -12 | | IIIV/ C |
| | Zero Gate Voltage Drain Current | V _{DS} = 16 V, V _{GS} = 0 V | Q1 | | | 1 | μА |
| I _{DSS} | Zero Gate Voltage Drain Current | $V_{DS} = -16 \ V, \ V_{GS} = 0 \ V$ | Q2 | | | -1 | μΑ |
| I _{GSS} | Gate to Source Leakage Current | $V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$ | All | | | ±10 | μΑ |

On Characteristics

| V _{GS(th)} | Gate to Source Threshold Voltage | $V_{GS} = V_{DS}, \ I_D = 250 \ \mu A$ $V_{GS} = V_{DS}, \ I_D = -250 \ \mu A$ | Q1 Q2 | 0.4 -0.4 | 0.7 -0.6 | 1.0 -1.0 | V |
|--|---|--|----------|-------------|-------------|-------------|-------|
| $\frac{\Delta V_{GS(th)}}{\Delta T_J}$ | Gate to Source Threshold Voltage Temperature Coefficient | I_D = 250 μ A, referenced to 25 °C | Q1 Q2 | | -3 2 | | mV/°C |
| | | $V_{GS} = 4.5 \text{ V}, I_D = 3.4 \text{ A}$ | | | 55 | 66 | |
| | | $V_{GS} = 2.5 \text{ V}, I_D = 2.9 \text{ A}$ | | | 68 | 86 | |
| | | $V_{GS} = 1.8 \text{ V}, I_D = 2.5 \text{ A}$ | Q1 | | 85 | 113 | - mΩ |
| | | $V_{GS} = 1.5 \text{ V}, I_D = 2.1 \text{ A}$ | Q1 | | 106 | 160 | |
| _ | | $V_{GS} = 4.5 \text{ V}, I_D = 3.4 \text{ A},$ $T_J = 125 ^{\circ}\text{C}$ | | | 76 | 112 | |
| r _{DS(on)} | Drain to Source On Resistance | $V_{GS} = -4.5 \text{ V}, I_D = -2.3 \text{ A}$ | | | 95 | 142 | |
| | | $V_{GS} = -2.5 \text{ V}, I_D = -1.8 \text{ A}$ | | | 120 | 213 | |
| | | $V_{GS} = -1.8 \text{ V}, I_D = -1.5 \text{ A}$ | Q2 | | 150 | 331 | |
| | | $V_{GS} = -1.5 \text{ V}, I_D = -1.2 \text{ A}$ | QZ | | 190 | 530 | |
| | | $V_{GS} = -4.5 \text{ V}, I_D = -2.3 \text{ A},$ $T_J = 125 ^{\circ}\text{C}$ | | | 128 | 190 | |
| 9 _{FS} | Forward Transconductance | $V_{DS} = 4.5 \text{ V}, I_{D} = 3.4 \text{ A}$ $V_{DS} = -4.5 \text{ V}, I_{D} = -2.3 \text{ A}$ | Q1 Q2 | | 9 7 | | S |

Dynamic Characteristics

| C _{iss} | Input Capacitance | Q1 | Q1 Q2 | 225 305 | 300 405 | pF |
|------------------|------------------------------|---|----------|------------|------------|----|
| C _{oss} | Output Capacitance | V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz Q2 | Q1 Q2 | 40 55 | 55 75 | pF |
| C _{rss} | Reverse Transfer Capacitance | $V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$ | Q1 Q2 | 25 50 | 40 75 | pF |

Switching Characteristics

| t _{d(on)} | Turn-On Delay Time | Q1 | Q1 Q2 | 4.5 4.7 | 10 10 | |
|---------------------|-------------------------------|--|----------|------------|------------|----|
| t _r | Rise Time | $V_{DD} = 10 \text{ V}, I_{D} = 1 \text{ A},$ $V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$ | Q1 Q2 | 2.0 4.8 | 10 10 | ns |
| t _{d(off)} | Turn-Off Delay Time | Q2 V _{DD} = -10 V, I _D = -1 A, | Q1 Q2 | 15 33 | 27 53 | |
| t _f | Fall Time | $V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$ | Q1 Q2 | 1.7 16 | 10 29 | |
| Qg | Total Gate Charge | Q1 V _{DD} = 10 V, I _D = 3.4 A, | Q1 Q2 | 3 5.5 | 4.2 7.7 | |
| Q _{gs} | Gate to Source Gate Charge | V _{GS} = 4.5 V Q2 | Q1 Q2 | 0.4 0.6 | | nC |
| Q _{gd} | Gate to Drain "Miller" Charge | $V_{DD} = -10 \text{ V}, I_{D} = -2.3 \text{ A}, V_{GS} = -4.5 \text{ V}$ | Q1 Q2 | 0.6 1.4 | | |

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

| Symbol | Parameter | Test Conditions | Туре | Min | Тур | Max | Units |
|-----------------|---------------------------------------|---|----------|-----|-------------|-------------|-------|
| Drain-Sou | urce Diode Characteristics | | | | | | |
| V _{SD} | Source to Drain Diode Forward Voltage | $V_{GS} = 0 \text{ V}, I_S = 0.9 \text{ A}$ (Note 2) $V_{GS} = 0 \text{ V}, I_S = -0.9 \text{ A}$ (Note 2) | | | 0.7 -0.8 | 1.2 -1.2 | V |
| t _{rr} | Reverse Recovery Time | Q1 I _F = 3.4 A, di/dt = 100 A/μS | | | 8.5 16 | 17 29 | ns |
| Q _{rr} | Reverse Recovery Time | Q2 I _F = -2.3 A, di/dt = 100 A/μs | Q1 Q2 | | 1.4 4.4 | 10 10 | nC |

Notes

Notes. 1. R_{0JA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.



a. 90 °C/W when mounted on a 1 in² pad of 2 oz copper.



 b. 195 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection ESD. No gate overvoltage rating is implied.

Typical Characteristics (Q1 N-Channel) T_J = 25°C unless otherwise noted

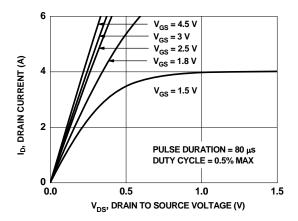


Figure 1. On Region Characteristics

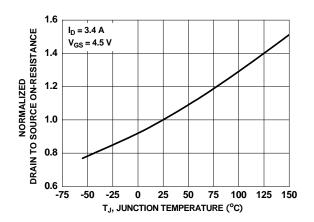


Figure 3. Normalized On Resistance vs Junction Temperature

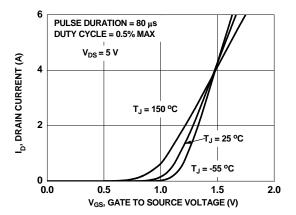


Figure 5. Transfer Characteristics

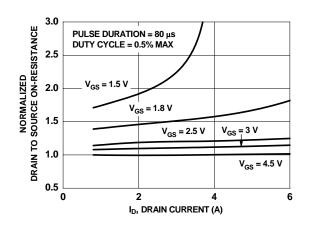


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

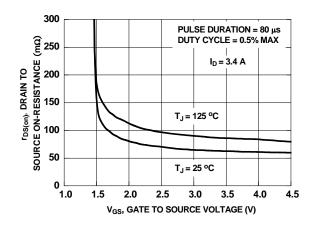


Figure 4. On-Resistance vs Gate to Source Voltage

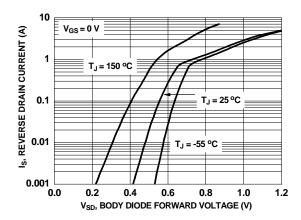


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q1 N-Channel) T_J = 25°C unless otherwise noted

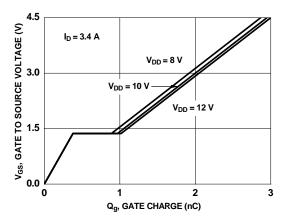


Figure 7. Gate Charge Characteristics

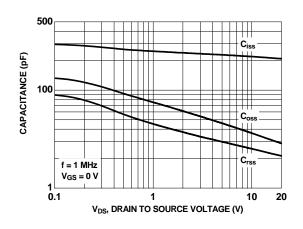


Figure 8. Capacitance vs Drain to Source Voltage

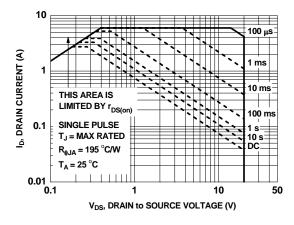


Figure 9. Forward Bias Safe Operating Area

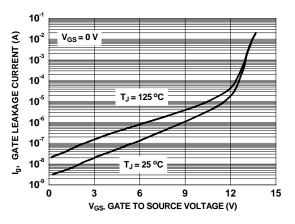


Figure 10. Gate Leakage Current vs Gate to Source Voltage

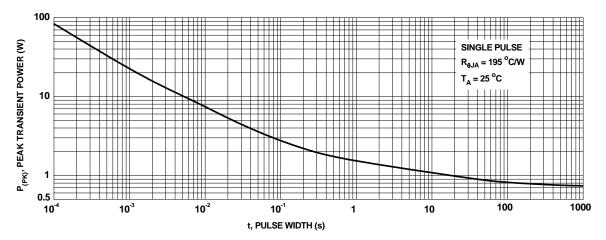


Figure 11. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q1 N-Channel) $T_J = 25$ °C unless otherwise noted

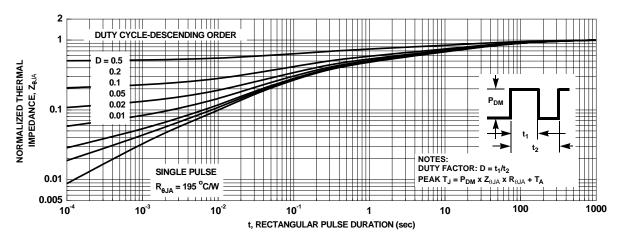


Figure 12. Junction-to-Ambient Transient Thermal Response Curve

Typical Characteristics (Q2 P-Channel) T_J = 25 °C unless otherwise noted

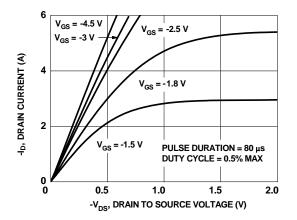


Figure 13. On- Region Characteristics

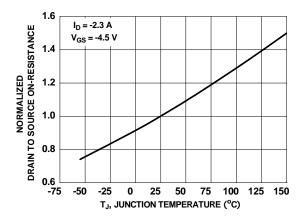


Figure 15. Normalized On-Resistance vs Junction Temperature

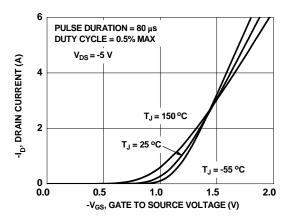


Figure 17. Transfer Characteristics

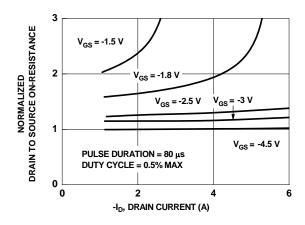


Figure 14. Normalized on-Resistance vs Drain Current and Gate Voltage

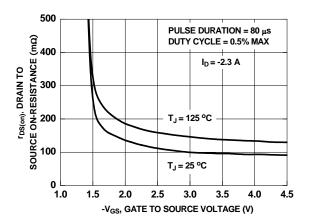


Figure 16. On-Resistance vs Gate to Source Voltage

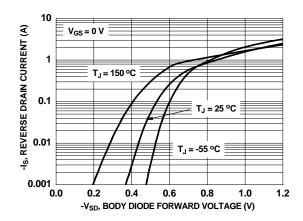


Figure 18. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q2 P-Channel) T_{.i} = 25°C unless otherwise noted

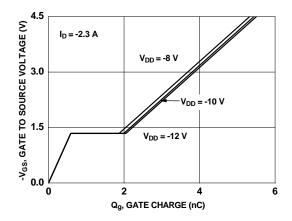


Figure 19. Gate Charge Characteristics

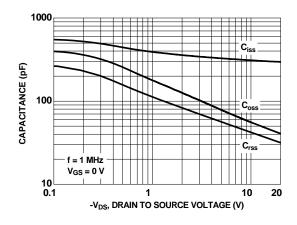


Figure 20. Capacitance vs Drain to Source Voltage

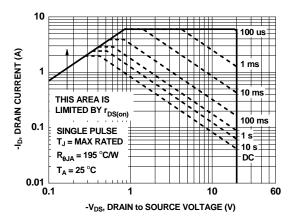


Figure 21. Forward Bias Safe Operating Area

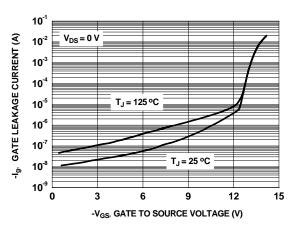


Figure 22. Gate Leakage Current vs Gate to Source Voltage

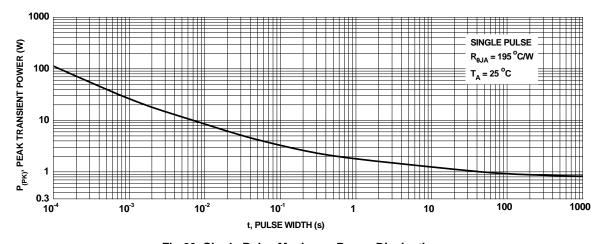


Fig 23. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q2 P-Channel) T_J = 25 °C unless otherwise noted

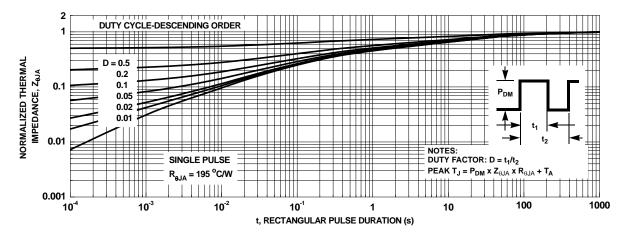
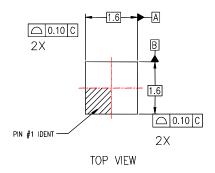
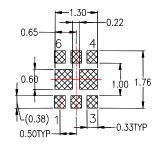


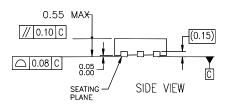
Figure 24. Junction-to-Ambient Transient Thermal Response Curve

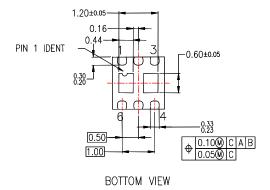
Dimensional Outline and Pad Layout





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